### FDD6630A

#### 30V N-Channel PowerTrench<sup>®</sup> MOSFET

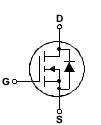
#### **General Description**

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low  $R_{DS(ON)}$  and fast switching speed.

#### Applications

- DC/DC converter
- Motor drives

# G S TO-252



• High performance trench technology for extremely

 $R_{\text{DS(ON)}} = 35 \text{ m}\Omega @ \text{V}_{\text{GS}} = 10 \text{ V}$ 

 $R_{DS(ON)} = 50 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$ 

#### Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V <sub>DSS</sub>	Drain-Source Voltage		30	V	
V <sub>GSS</sub>	Gate-Source Voltage		±20	V	
b	Drain Current – Continuous	(Note 3)	21	А	
	- Pulsed	(Note 1a)	100		
PD	Power Dissipation	(Note 1)	28	W	
		(Note 1a)	3.2		
		(Note 1b)	1.3		
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range		-55 to +175	°C	
Therma	I Characteristics				
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	4.5	°C/W	

Features

• 21 A, 30 V

· Fast switching

low R<sub>DS(ON)</sub>

.

• Low gate charge (5nC typical)

### R<sub>0JA</sub> Thermal Resistance, Junction-to-Ambient (Note 1a) 40 °C/W R<sub>0JA</sub> Thermal Resistance, Junction-to-Ambient (Note 1b) 96 °C/W

#### **Package Marking and Ordering Information**

Device Marking	Device	Reel Size	Tape width	Quantity
FDD6630A FDD6630A		13"	16mm	2500 units

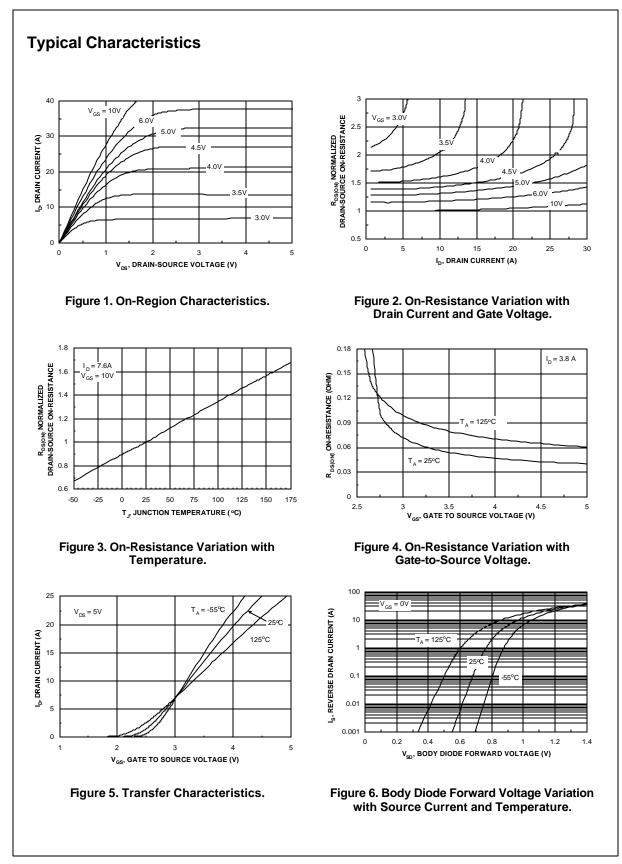
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Parameter	Test Conditions	Min	Тур	Мах	Units
Irce Avalanche Ratings (Note	2)		1		
Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 15 V$			55	mJ
Drain-Source Avalanche Current				7.6	Α
cteristics					
Drain–Source Breakdown Voltage	$V_{GS} = 0 V, I_D = 250 \mu A$	30			V
Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$ , Referenced to $25^{\circ}\text{C}$		23		mV/⁰C
Zero Gate Voltage Drain Current	$V_{\text{DS}} = 24 \text{ V},  V_{\text{GS}} = 0 \text{ V}$			1	μA
Gate–Body Leakage, Forward				100	nA
Gate–Body Leakage, Reverse	$V_{GS} = -20 \text{ V},  V_{DS} = 0 \text{ V}$			-100	nA
cteristics (Note 2)					
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	1	1.7	3	V
Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 µA, Referenced to 25°C		-4		mV/ºC
Static Drain–Source On–Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 6.3 \text{ A}$		28 40 44	35 50 58	mΩ
On–State Drain Current	$V_{GS} = 10 \text{ V},  V_{DS} = 5 \text{ V}$	20			А
Forward Transconductance	$V_{DS} = 5 V$ , $I_{D} = 7.6 A$		13		S
Characteristics	I		1	1	
Input Capacitance	$V_{DS} = 15 V$ , $V_{GS} = 0 V$ ,		462		pF
Output Capacitance	f = 1.0 MHz		113		pF
Reverse Transfer Capacitance			40		pF
Characteristics (Note 2)	•				
Turn–On Delay Time	$V_{DD} = 15 V$ , $I_D = 1 A$ ,		5	11	ns
Turn–On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		8	17	ns
Turn–Off Delay Time			17	28	ns
Turn–Off Fall Time			13	24	ns
Total Gate Charge			5	7	nC
Gate-Source Charge	$V_{GS} = 5 V$		2		nC
Gate–Drain Charge			1.4		nC
urce Diode Characteristics	and Maximum Ratings				
Maximum Continuous Drain–Source	Diode Forward Current			2.7	А
Drain–Source Diode Forward	$V_{GS} = 0 V$ , $I_S = 2.7 A$ (Note 2)		0.8	1.2	V
	Cteristics         Drain–Source Breakdown Voltage         Breakdown Voltage Temperature         Coefficient         Zero Gate Voltage Drain Current         Gate–Body Leakage, Forward         Gate–Body Leakage, Reverse         Cteristics (Note 2)         Gate Threshold Voltage         Comperature Coefficient         Static Drain–Source         Dn–Resistance         Dn–State Drain Current         Forward Transconductance         Characteristics         Noute 2)         Current Capacitance         Dutput Capacitance         Reverse Transfer Capacitance         Characteristics (Note 2)         Furn–On Delay Time         Furn–On Rise Time         Furn–Off Delay Time         Furn–Off Fall Time         Fotal Gate Charge         Gate–Source Charge         Gate–Drain Charge	CteristicsDrain–Source Breakdown Voltage $V_{GS} = 0 \text{ V}, \text{ b} = 250 \ \mu\text{A}$ Breakdown Voltage Temperature Coefficient $\text{b} = 250 \ \mu\text{A}, \text{ Referenced to } 25^{\circ}\text{C}$ Zero Gate Voltage Drain Current $V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$ Sate–Body Leakage, Forward $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$ Sate–Body Leakage, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Sate–Body Leakage, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Sate–Body Leakage, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Sate Threshold Voltage $V_{DS} = V_{GS}, \text{ b} = 250 \ \mu\text{A}$ Sate Threshold Voltage $V_{DS} = V_{GS}, \text{ b} = 250 \ \mu\text{A}$ Sate Threshold Voltage $V_{DS} = 10 \text{ V}, \text{ b} = 7.6 \text{ A}$ V_{GS} = 10 V, \text{ b} = 7.6 \text{ A}, V_{GS} = 10 \text{ V}, \text{ b} = 7.6 \text{ A}Dn–Resistance $V_{DS} = 5 \text{ V}, \text{ b} = 7.6 \text{ A}$ Dn–State Drain Current $V_{GS} = 10 \text{ V}, \text{ b} = 7.6 \text{ A}$ Characteristicsnput CapacitanceNput Capacitance $V_{DS} = 5 \text{ V}, \text{ b} = 7.6 \text{ A}$ Characteristics (Note 2)f= 1.0 \text{ MHz}Furm–On Delay Time $V_{DD} = 15 \text{ V}, \text{ b} = 1 \text{ A}, \text{ V}_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$ Furm–Off Delay Time $V_{DS} = 15 \text{ V}, \text{ b} = 7.6 \text{ A}, \text{ V}_{GS} = 5 \text{ V}$ Fotal Gate Charge $V_{DS} = 15 \text{ V}, \text{ b} = 7.6 \text{ A}, \text{ V}_{GS} = 5 \text{ V}$	CteristicsDrain–Source Breakdown Voltage $V_{GS} = 0 V$ , $b = 250 \mu A$ 30Breakdown Voltage Temperature Coefficient $b = 250 \mu A$ , Referenced to $25^{\circ}C$ 30Zero Gate Voltage Drain Current $V_{DS} = 24 V$ , $V_{GS} = 0 V$ 33Sate–Body Leakage, Forward $V_{GS} = 20 V$ , $V_{DS} = 0 V$ 34Sate–Body Leakage, Reverse $V_{GS} = -20 V$ , $V_{DS} = 0 V$ 34Sate–Body Leakage, Reverse $V_{GS} = -20 V$ , $V_{DS} = 0 V$ 34Sate–Body Leakage, Reverse $V_{GS} = -20 V$ , $V_{DS} = 0 V$ 36Sate–Body Leakage, Reverse $V_{GS} = -20 V$ , $V_{DS} = 0 V$ 1Sate–Body Leakage, Reverse $V_{GS} = -20 V$ , $V_{DS} = 0 V$ 1Sate–Body Leakage, Reverse $V_{GS} = -20 V$ , $V_{DS} = 0 V$ 1Sate–Body Leakage, Reverse $V_{GS} = -20 V$ , $V_{DS} = 0 V$ 1Sate–Body Leakage, Reverse $V_{DS} = V_{GS}$ , $b = 250 \mu A$ 1Sate–Threshold Voltage $b = 250 \mu A$ , Referenced to $25^{\circ}C$ 1Sate Threshold Voltage $V_{DS} = 10 V$ , $b = 7.6 A$ 1Sate Threshold Voltage $V_{GS} = 10 V$ , $V_{DS} = 5 V$ 20On–State Drain Current $V_{GS} = 15 V$ , $V_{CS} = 0 V$ ,1Duptu Capacitance $V_{DS} = 15 V$ , $V_{S} = 0 V$ ,1Duptu Capacitance $V_{DS} = 10 V$ , $R_{GEN} = 6 \Omega$ 1Furm–On Delay Time $V_{OS} = 10 V$ , $R_{GEN} = 6 \Omega$ 1Furm–On Rise Time $V_{OS} = 5 V$ $b = 7.6 A$ ,1Gate–Source Charge $V_{DS} = 5 V$ $b = 7.6 A$ ,1Sate–Sourc	CteristicsDrain–Source Breakdown Voltage $V_{GS} = 0$ V, $b = 250 \ \mu$ A, Referenced to $25^{\circ}$ C23Sreakdown Voltage Temperature $b = 250 \ \mu$ A, Referenced to $25^{\circ}$ C23Coefficient $V_{DS} = 24$ V, $V_{GS} = 0$ V23Zero Gate Voltage Drain Current $V_{DS} = 24$ V, $V_{DS} = 0$ V23Gate–Body Leakage, Forward $V_{GS} = 20$ V, $V_{DS} = 0$ V23Sate–Body Leakage, Reverse $V_{GS} = -20$ V, $V_{DS} = 0$ V23Sate–Body Leakage, Reverse $V_{GS} = -20$ V, $V_{DS} = 0$ V24Sate Threshold Voltage $b = 250 \ \mu$ A, Referenced to $25^{\circ}$ C-4Sate Threshold Voltage $b = 250 \ \mu$ A, Referenced to $25^{\circ}$ C-4Femperature Coefficient $b = 250 \ \mu$ A, Referenced to $25^{\circ}$ C-4Static Drain–Source $V_{GS} = 10 \ V$ , $b = 7.6 \ A$ 28On–State Drain Current $V_{GS} = 10 \ V$ , $b = 7.6 \ A$ , $T_J = 125^{\circ}$ C44On–State Drain Current $V_{GS} = 10 \ V$ , $V_{DS} = 5 \ V$ 20Forward Transconductance $V_{DS} = 5 \ V$ , $b = 7.6 \ A$ 13Characteristics(Note 2)462Dutput Capacitance $V_{DS} = 15 \ V$ , $b = 1 \ A$ , $V_{GS} = 10 \ V$ , $R_{SEN} = 6 \ \Omega$ 8Turn–On Delay Time $V_{OS} = 15 \ V$ , $b = 7.6 \ A$ , $5$ 8Turn–Off Eall Time1317Turn–Off Fall Time1313Total Gate Charge $V_{OS} = 5 \ V$ 2Sate–Source Charge $V_{OS} = 5 \ V$ 2Sate–Source Charge $V_{OS} = 5 \ V$ 2Sat	CeteristicsDrain-Source Breakdown Voltage $V_{GS} = 0$ V, $b = 250 \ \mu$ A, Referenced to $25^{\circ}$ C23Zero Gate Voltage Drain Current $V_{DS} = 24$ V, $V_{GS} = 0$ V1Date-Body Leakage, Forward $V_{GS} = 20$ V, $V_{DS} = 0$ V100Bate-Body Leakage, Reverse $V_{GS} = -20$ V, $V_{DS} = 0$ V-100Cetristics(Note 2)Bate Threshold Voltage $V_{DS} = V_{GS}$ , $b = 250 \ \mu$ A, Referenced to $25^{\circ}$ C-4Static Drain-Source Coefficient $b = 250 \ \mu$ A, Referenced to $25^{\circ}$ C-4Static Drain-Source $V_{GS} = 10$ V, $b = 7.6$ A, $T_J = 125^{\circ}$ C44On-Resistance $V_{GS} = 10$ V, $V_{DS} = 5$ V20Drace Transconductance $V_{DS} = 5$ V, $b = 7.6$ A13Characteristics $V_{DS} = 15$ V, $V_{CS} = 0$ V, $deS = 0$ V, $deS = 0$ V, $deS = 0$ Dupt Capacitance $V_{DS} = 15$ V, $V_{CS} = 0$ V, $deS = 0$ V, $deS = 0$ V, $deS = 0$ V, $deS = 0$ Dupt Capacitance $V_{DS} = 15$ V, $b = 7.6$ A13Characteristics(Note 2)Turn-On Delay Time $V_{DD} = 15$ V, $b = 1$ A, $V_{CS} = 10$ V, $R_{GEN} = 6$ $\Omega$ 8Turn-Off Delay Time $V_{DS} = 15$ V, $b = 7.6$ A, $5$ 7Turn-Off Fall Time $V_{OS} = 15$ V, $b = 7.6$ A, $5$ 7Cate-Source Charge $V_{OS} = 5$ V $2$ Sate-Drain Charge $V_{OS} = 15$ V, $b = 7.6$ A, $5$ 7Cate-Charge $2$ $3$ $3$ Characteristics $10$ V, $R_{S} = 10$ V, $R_{S} = 5$ V $2$ Characteristics $11$ V, $R_{S} = 10$ V, $R_{S} $

2. Pulse Test: Pulse Width < 300 $\mu$ s, Duty Cycle < 2.0%

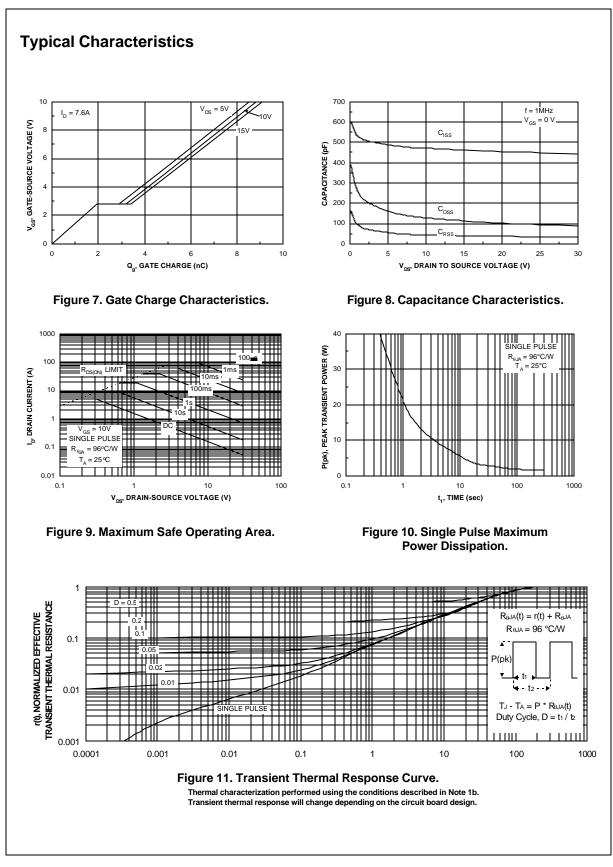
3. Maximum current is calculated as:  $\sqrt{\frac{P_U}{R_{Res,res,i}}}$ where P<sub>D</sub> is maximum power dissipation at T<sub>C</sub> = 25°C and R<sub>DS(on)</sub> is at T<sub>J(max)</sub> and V<sub>GS</sub> = 10V. Package current limitation is 21A FDD6630A

FDD6630A Rev. D(W)



## FDD6630A

FDD6630A Rev. D(W)



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